SERESSA International School 12-16 Nov. 2018

Tuesday 13 November 2018

<u>Tests and simulations</u> - Newton 1-2 (14:30 - 18:00)

time	[id] title	presenter
	[24] Accurate Abstraction and High Level Modeling and Validation of SEE in Electronic Systems	Dr AIT MOHAMED, Otmane
15:30	[25] Fault Injection Methodologies	Prof. ENTRENA ARRONTES, Luis
17:00	[21] Error-rate Prediction for Programmable Circuits: Methodology, Tools and Studied Cases	Dr VELAZCO, Raoul

Wednesday 14 November 2018

Tests and simulations - Newton 1-2 (14:30 - 18:00)

time [id] title	presenter
14:30 [22] Microprocessor testing: characterization tests, mitigation	QUINN, Heather
15:30 [26] Multi and Many core Processors: Fault tolerance and Radiation tests	Prof. RAMOS, Pablo Prof. VARGAS, Vanessa Dr VELAZCO, Raoul
17:00 [23] Radiation tests of advanced SRAM memories	Dr CLEMENTE, Juan

Thursday 15 November 2018

Tests and simulations - Newton 1-2 (09:30 - 10:30)

time [id] title	presenter
09:30 [27] Laser Testing: Laser Simulation Test Possibilities and Facilities	MCMORROW, Dale